## TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

# **T6B23**

## COLUMN DRIVER LSI FOR A DOT MATRIX LCD

The T6B23 is a column driver with  $80\ \text{output}$  channels for a dot matrix LCD.

The T6B23 realizes low power consumption using the CMOS Si-Gate process. The T6B23 has two types of data flow:

(1)  $O_1 \rightarrow O_{80}$ , (2)  $O_{80} \rightarrow O_1$ .

## **FEATURES**

• 80-output column driver

Data input format: ENABLE mode: SHIFT mode

• Two types of data flow:

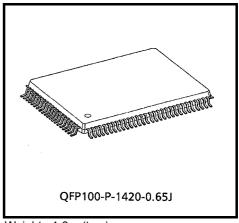
(1)  $O_1 \rightarrow O_{80}$ (2)  $O_{80} \rightarrow O_1$ 

• Low power consumption

• Logic voltage  $: 5.0V \pm 10\%$ 

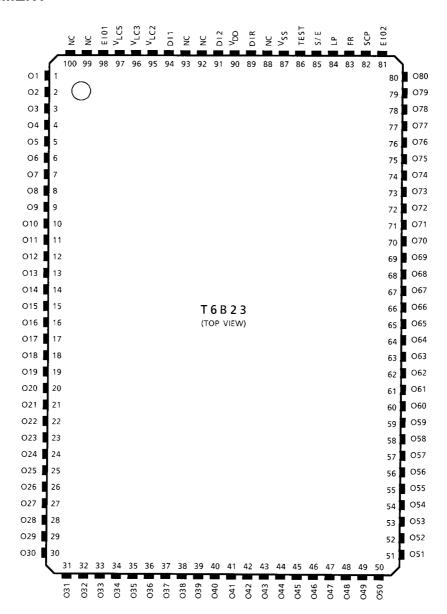
LCD drive voltage : V<sub>DD</sub> − 3.0V to V<sub>DD</sub> − 11.0V

• 100-pin plastic flat package



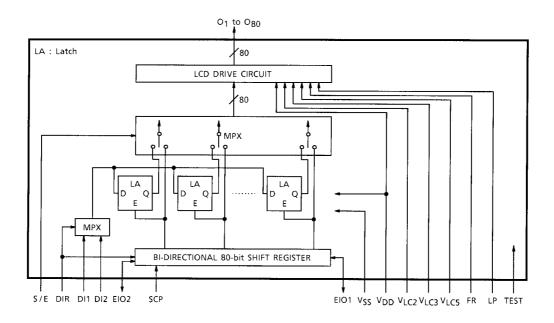
Weight: 1.6 g (typ.)

## **PIN ASSIGNMENT**



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# **BLOCK DIAGRAM**



# **PIN FUNCTIONS**

PIN NAME	1/0	FUNCTIONS	LEVEL
O1 to O80	Output	LCD drive output	V <sub>DD</sub> to V <sub>LC5</sub>
DI1, DI2	Input	Data signal input	
EIO1, EIO2	1/0	ENABLE I / O When S / E = H, this pin is for input.	
SCP	Input	(Shift Clock Pulse) Shift clock pulse input	
FR	Input	(Frame) Frame signal input	V <sub>DD</sub> to V <sub>SS</sub>
LP	Input	(Latch Pulse) Latch pulse signal input	
S/E	Input	Extension driver select input	
DIR	Input	Input data flow direction select input	
TEST	Input	Test pin: usually connected to V <sub>SS</sub> .	
V <sub>LC2, 3, 5</sub>	_	Power supply for LCD drive	
$V_{DD}$	_	Power supply (5V)	_
V <sub>SS</sub>	_	Power supply (0V)	

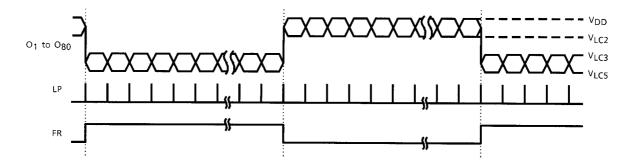
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## **FUNCTION OF DATA AND ENABLE PINS**

S / DI		DI1	DI2	EIO1	EIO2	DATA FLOW	FIRST DATA	LAST DATA	MODE
L	L	Open	DATA INPUT	ENABLE signal input	ENABLE signal output	$O_{80} \rightarrow O_1$	O <sub>1</sub>	O <sub>80</sub>	ENABLE
L	Н	DATA INPUT	Open	ENABLE signal output	ENABLE signal input	$O_1 \rightarrow O_{80}$	O <sub>80</sub>	O <sub>1</sub>	LIVABLE
Н	L	Open	Open	DATA INPUT	DATA OUTPUT	$O_1 \rightarrow O_{80}$	O <sub>80</sub>	O <sub>1</sub>	SHIFT
Н	Н	Open	Open	DATA OUTPUT	DATA INPUT	$O_{80} \rightarrow O_1$	O <sub>1</sub>	O <sub>80</sub>	OI III I

## **TIMING DIAGRAM**



# ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

ITEM	SYMBOL	RATING	UNIT
Supply Voltage (1)	V <sub>DD</sub> (Note 1)	- 0.3 to 7.0	V
Supply Voltage (2)	V <sub>LC2</sub> , V <sub>LC3</sub> , V <sub>LC5</sub> (Note1, 2)	V <sub>DD</sub> - 12.0 to V <sub>DD</sub> + 0.3	V
Input Voltage	V <sub>IN</sub> (Note 1)	- 0.3 to V <sub>DD</sub> + 0.3	V
Operating Temperature	T <sub>opr</sub>	- 20 to 75	°C
Storage Temperature	T <sub>stg</sub>	- 55 to 125	°C

Note 1: Referenced to V<sub>SS</sub> = 0 V

Note 2: Ensure that the following condition is always maintained.

 $V_{DD}{\geq}V_{LC2}{\geq}V_{LC3}{\geq}V_{LC5}.$ 

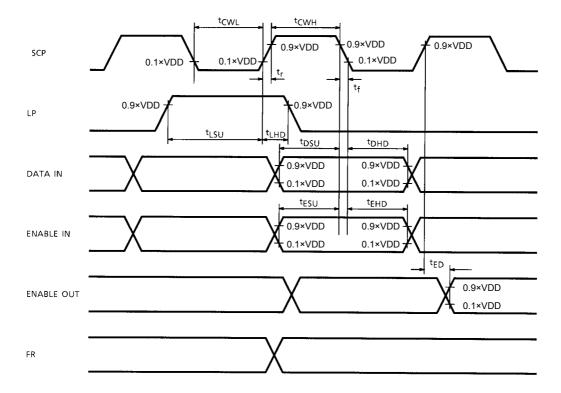
# ELECTRICAL CHARACTERISTICS DC CHARACTERISTICS

TEST CONDITIONS (Unless Otherwise Noted,  $V_{SS}$  = 0 V,  $V_{DD}$  = 5.0 V ± 10%,  $V_{LC5}$  = 0V,  $T_{a}$  = -20 to 75°C)

ITEM SYM		SYMBOL	TEST CIR- CUIT	TEST CONDITION		MIN	TYP.	MAX	UNIT	PIN NAME
Operating Voltage (1)		$V_{DD}$	_	_		4.5	5.0	5.5	V	$V_{DD}$
Operating Voltage (2)		VLC5	_	_		V <sub>DD</sub> - 11.0	_	V <sub>DD</sub> - 3.0	V	VLC5
Input Voltage	H Level	V <sub>IH</sub>	_	_		V <sub>DD</sub> - 1.0	_	V <sub>DD</sub>	٧	(*)
input Voltago	L Level	V <sub>IL</sub>		_		0	_	1.0	٧	(*)
Output	H Level	V <sub>OH</sub>	-	I <sub>OH</sub> = -0.4 mA		V <sub>DD</sub> - 0.4	_	V <sub>DD</sub>	٧	EIO1, EIO2
Voltage	L Level	V <sub>OL</sub>		I <sub>Oh</sub> = 0.4 mA		0	_	0.4	V	EIO1, EIO2
Output Resistance		R <sub>COL</sub>	_	$I_d = \pm 50 \mu A$		_	-	30	kΩ	O <sub>1</sub> to O <sub>80</sub>
Operating Frequency		f <sub>scp</sub>	_	Ta = -20to 75°C		_	-	400	kHz	SCP
Current Consumption			V <sub>DD</sub> = 5.0 V V <sub>LC2</sub> = 3.0 V V <sub>LC3</sub> = 2.0 V	Binary Data Input	_	_	1.0	mA		
		I <sub>SS</sub>	- V <sub>LC5</sub> = 0 f <sub>FR</sub> = 39 f <sub>SCP</sub> = 2 0 <sub>1</sub> to 0 <sub>80</sub>	$V_{LC5} = 0.0 \text{ V}$ $f_{FR} = 39 \text{ Hz}$ $f_{SCP} = 250 \text{ kHz}$ $0_1 \text{ to } 0_{80}$ :No Load	Input Data : LOW Constant		l	0.4	mA	V <sub>SS</sub>

<sup>\*:</sup> SCP, LP, FR, EIO1, EIO2, DI1, DI2, DIR, S / E, TEST

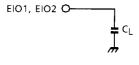
## **AC CHARACTERISTICS**



TEST CONDITIONS (Unless Otherwise Noted,  $V_{SS}$  = 0 V,  $V_{DD}$  = 5 V  $\pm$  10%,  $V_{LC5}$  = 0 V, Ta = -20 to 75°C)

ITEM	SY	SYMBOL		MAX	UNIT
Operating Frequency	f <sub>SCP</sub>	f <sub>SCP</sub>		400	KHz
SCP Pulse Width	t <sub>CWH</sub> , t <sub>C</sub>	t <sub>CWH</sub> , t <sub>CWL</sub>		_	ns
SCP Rise / Fall Time	t <sub>r</sub> , t <sub>f</sub>		_	200	ns
LP Set-up Time	t <sub>LSU</sub>		500	_	ns
LP Hold Time	t <sub>LHD</sub>		_	10	ns
Data Set-up Time	t <sub>DSU</sub>	(Note 1)	300	_	ns
Data Hold Time	t <sub>DHD</sub>	(Note 1)	300	_	ns
Enable Set-up Time	tESU	(Note 2)	300	_	ns
Enable Hold Time	t <sub>EHD</sub>	(Note 2)	300	_	ns
Enable Delay Time	t <sub>ED</sub>	(Note 3)	_	500	ns

**LOAD CIRCUIT** 



C<sub>L</sub> = 50pF (including wiring capacitance)

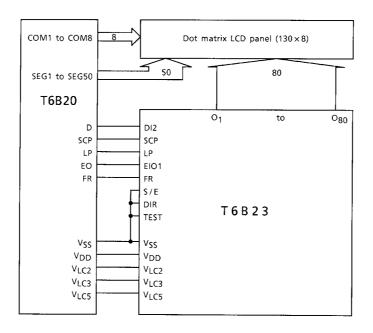
Note 1: Applies to DI1 and DI2.

Note 2: Applies to EIO1 and EIO2.

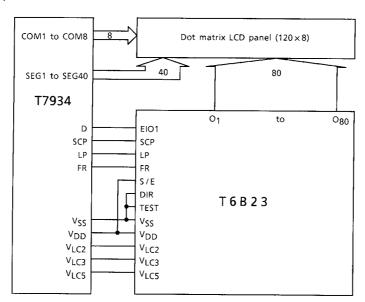
Note 3: With load circuit connected

## **APPLICATION CIRCUIT**

#### (a) S / E = L (ENABLE mode)



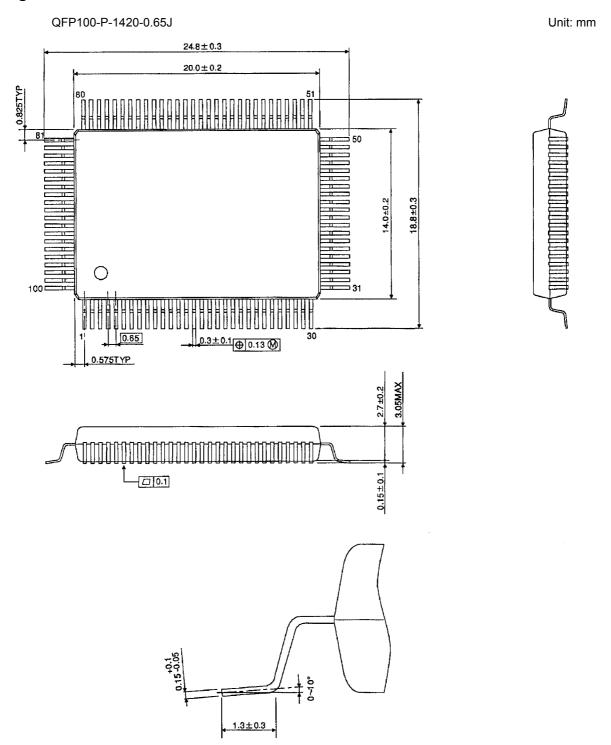
## (b)S / E = H (SHIFT mode)



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# **Package Dimensions**



Weight: 1.6 g (Typ.)

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